

# FDP150N10

## N-Channel PowerTrench® MOSFET

100V, 57A, 15mΩ

### Features

- $R_{DS(on)} = 12m\Omega$  (Typ.) @  $V_{GS} = 10V, I_D = 49A$
- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low  $R_{DS(on)}$
- High power and current handling capability
- RoHS compliant

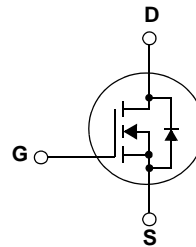
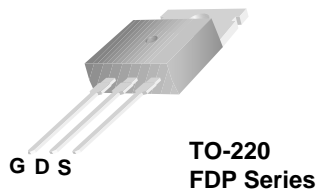


### General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

### Application

- DC to DC convertors / Synchronous Rectification



### MOSFET Maximum Ratings $T_C = 25^\circ C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain to Source Voltage	100	V
$V_{GSS}$	Gate to Source Voltage	$\pm 20$	V
$I_D$	Drain Current	-Continuous ( $T_C = 25^\circ C$ )	57
		-Continuous ( $T_C = 100^\circ C$ )	40
$I_{DM}$	Drain Current	- Pulsed (Note 1)	228
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	132
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	7.5
$P_D$	Power Dissipation	( $T_C = 25^\circ C$ )	110
		- Derate above $25^\circ C$	0.88
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ C$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ C$

### Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.13	$^\circ C/W$
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	

**Package Marking and Ordering Information**  $T_C = 25^\circ\text{C}$  unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP150N10	FDP150N10	TO-220	-	-	50

**Electrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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**Off Characteristics**

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_C = 25^\circ\text{C}$	100	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	-	0.1	-	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}, T_C = 150^\circ\text{C}$	-	-	500	
$I_{GSS}$	Gate to Body Leakage Current	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	2.5	-	4.5	V
$R_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 49\text{A}$	-	12	15	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 20\text{V}, I_D = 49\text{A}$ (Note 4)	-	156	-	S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	3580	4760	pF
$C_{oss}$	Output Capacitance		-	340	450	pF
$C_{rss}$	Reverse Transfer Capacitance		-	140	210	pF

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 50\text{V}, I_D = 49\text{A}$ $V_{GS} = 10\text{V}, R_{GEN} = 25\Omega$ (Note 4, 5)	-	47	104	ns	
$t_r$	Turn-On Rise Time		-	164	338	ns	
$t_{d(off)}$	Turn-Off Delay Time		-	86	182	ns	
$t_f$	Turn-Off Fall Time		-	83	176	ns	
$Q_{g(tot)}$	Total Gate Charge at 10V		$V_{DS} = 80\text{V}, I_D = 49\text{A}$	-	53	69	nC
$Q_{gs}$	Gate to Source Gate Charge		$V_{GS} = 10\text{V}$	-	19	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note 4, 5)	-	15	-	nC	

**Drain-Source Diode Characteristics**

$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	57	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	228	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 49\text{A}$	-	-	1.3	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 49\text{A}$	-	41	-	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt = 100\text{A}/\mu\text{s}$ (Note 4)	-	70	-	nC

**Notes:**

- 1: Repetitive Rating: Pulse width limited by maximum junction temperature
- 2:  $L = 0.11\text{mH}, I_{AS} = 49\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
- 3:  $I_{SD} \leq 49\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
- 4: Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
- 5: Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

Figure 1. On-Region Characteristics

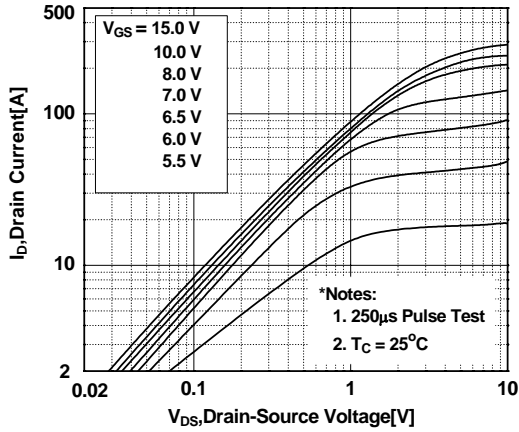


Figure 2. Transfer Characteristics

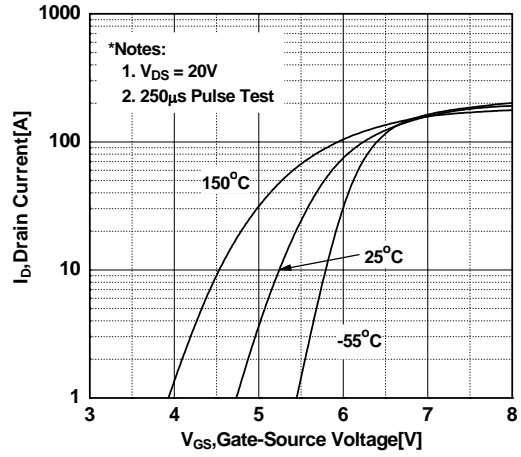


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

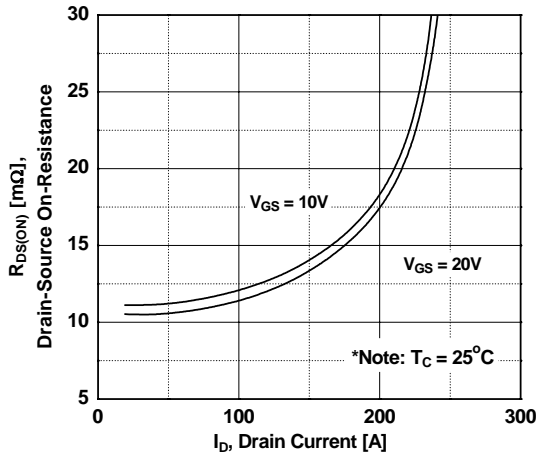


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

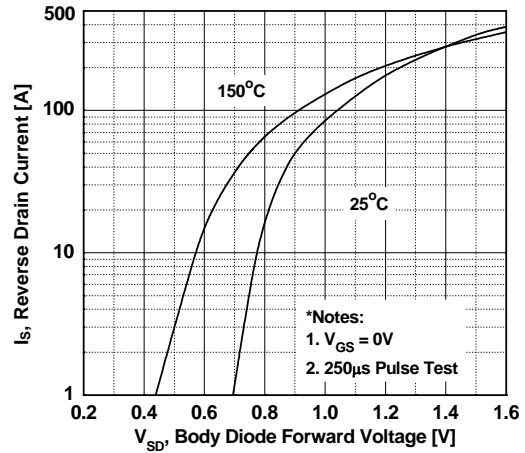


Figure 5. Capacitance Characteristics

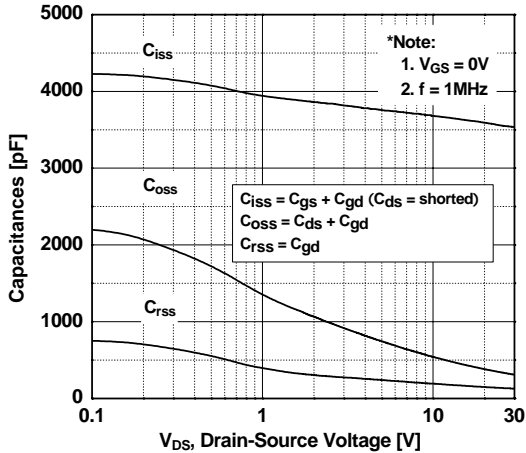
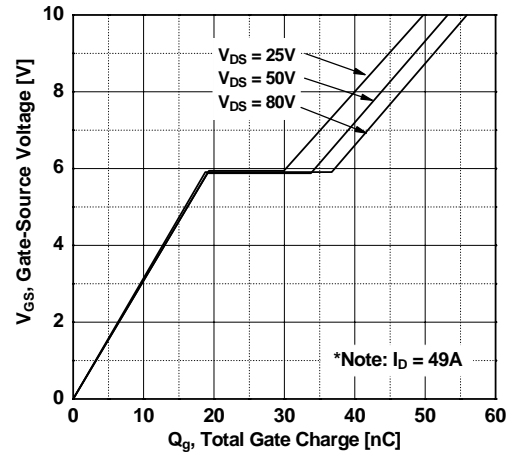
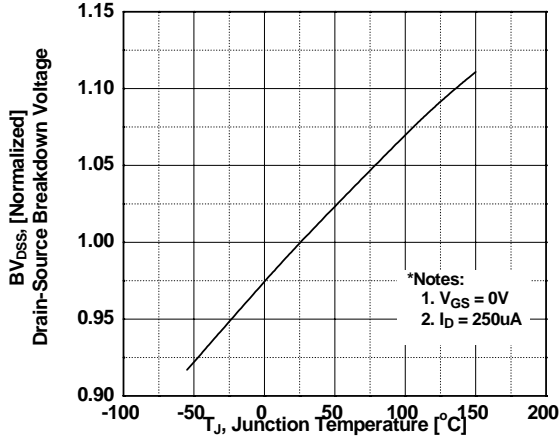


Figure 6. Gate Charge Characteristics

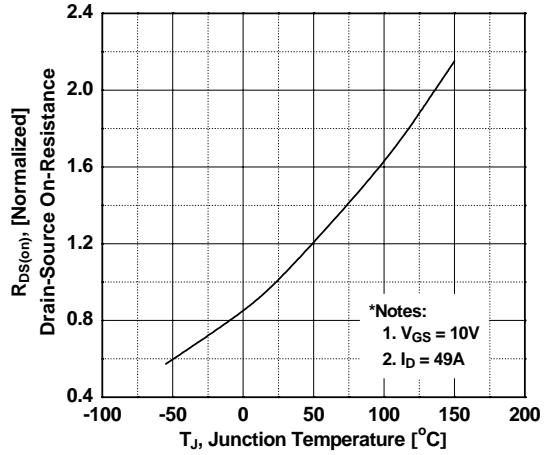


**Typical Performance Characteristics** (Continued)

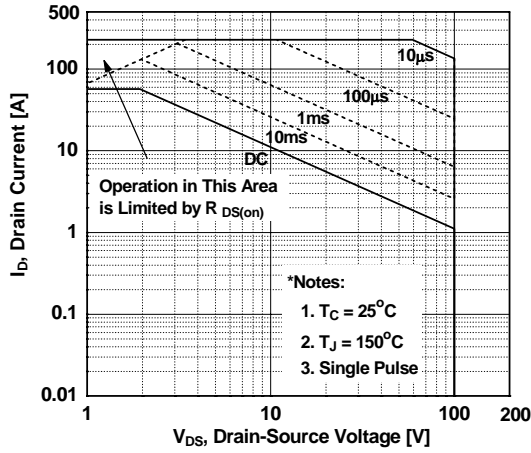
**Figure 7. Breakdown Voltage Variation vs. Temperature**



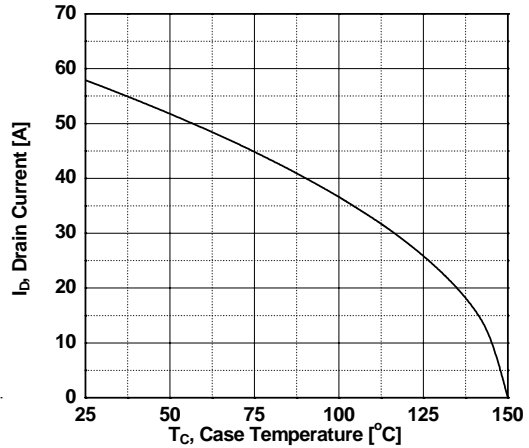
**Figure 8. On-Resistance Variation vs. Temperature**



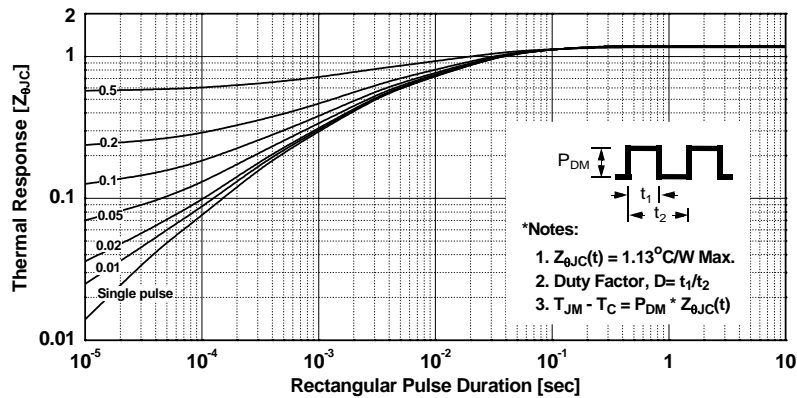
**Figure 9. Maximum Safe Operating Area**



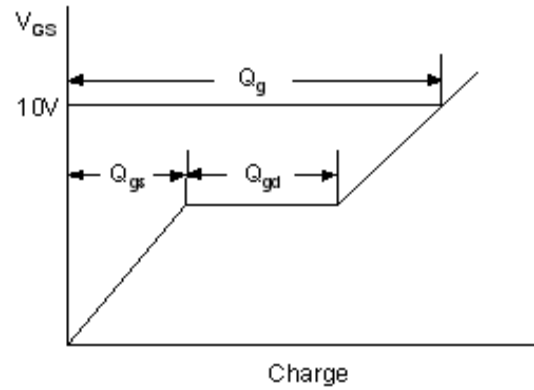
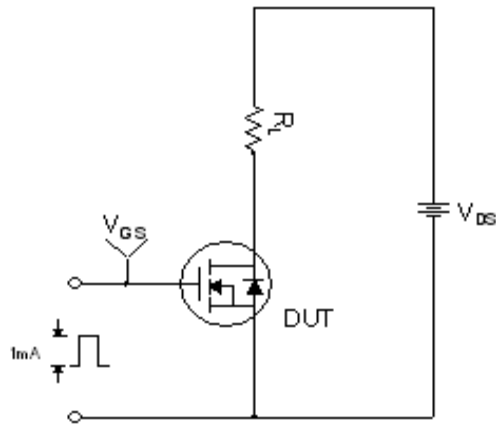
**Figure 10. Maximum Drain Current vs. Case Temperature**



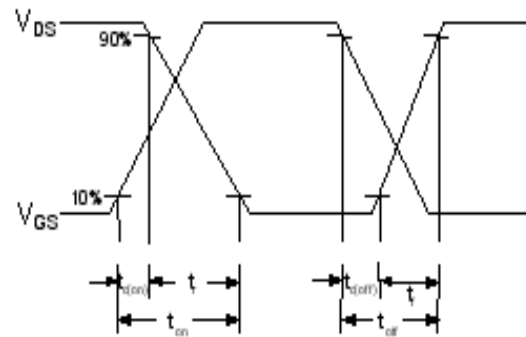
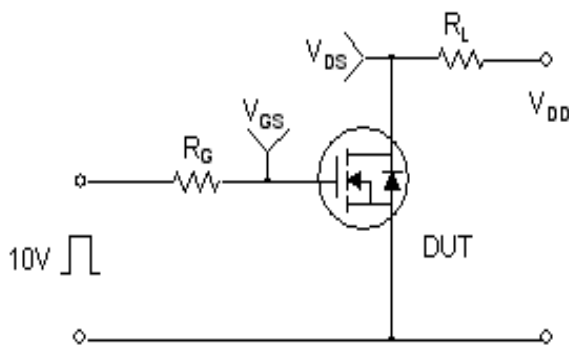
**Figure 11. Transient Thermal Response Curve**



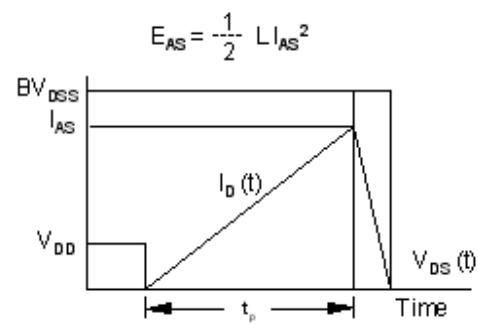
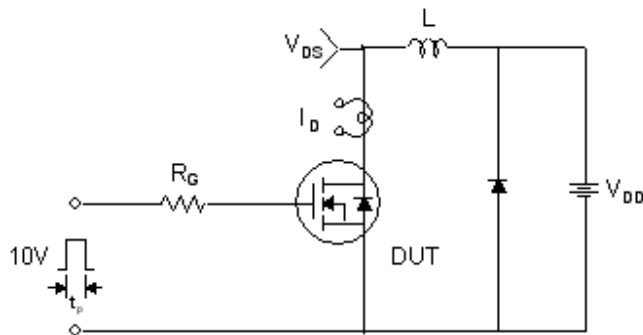
**Gate Charge Test Circuit & Waveform**



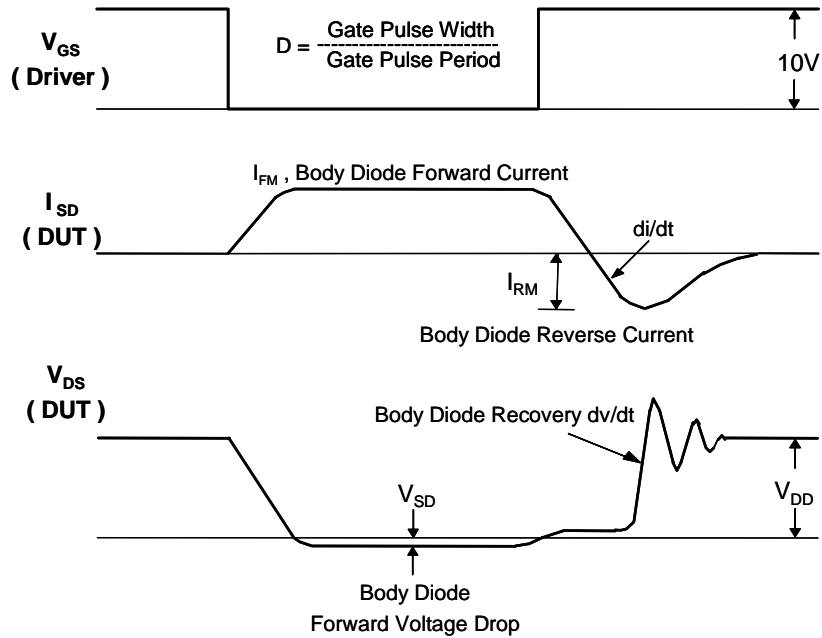
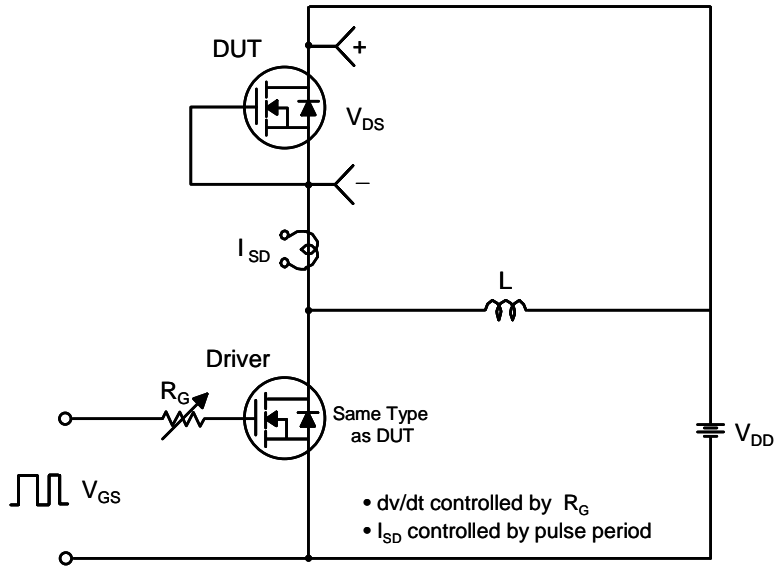
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**



Peak Diode Recovery dv/dt Test Circuit & Waveforms











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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
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